


<b>Search Notes</b>  	<b>Application/Control No.</b>  10823400	<b>Applicant(s)/Patent Under Reexamination</b>  BAUER ET AL.
	<b>Examiner</b>  Tae H Yoon	<b>Art Unit</b>  1796

SEARCHED			
Class	Subclass	Date	Examiner
524	437	2/16/2008	/TY/

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	2/16 and 2/18/2008	/TY/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner